# SITA Process Solutions NEURTEK



# SITA CLEAN LINE CI

# **Inline Inspection** of Cleanliness



- ✓ Highest product quality through controlled cleaning
- ✓ Contact-free cleanliness control
- ✓ Documentation of lowest contamination levels
- ✓ System solution for high process security
- $\checkmark$  Cost effectiveness through process optimization

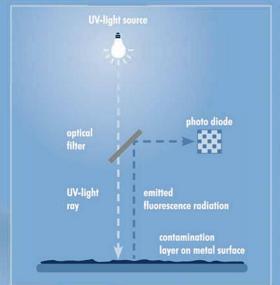
# **SITA** Process Solutions



## SITA CLEAN LINE CO Inline Cleanliness Inspection of Surfaces

The inline fluorescence measurement technology SITA clean line CI is optimal for a continual cleanliness control in cleaning processes. Slight traces of contamination such as oils, greases, cooling lubricants or surfactants cause quality defects in following surface treatment and surface coating processes leading to higher costs. A regular inspection of part surfaces ensures that the required cleanliness levels are maintained. Further actions such as dosing up the cleaning agent components or bath care can be initiated immediately if the part cleanliness decreases.

### **Measuring Principle**



Typical contamination in industrial manufacturing processes such as oils, greases or surfactants fluoresce when being excited by ultra violet light. The measured intensity of fluorescence radiation increases with the thickness of the contamination layer.

An integrated UV-LED stimulates the excitatian of the fluorescence. A photo-diode measures the intensity of the resulting fluorescence radiation. The calibration of the cleanliness takes place on reference parts defined as being 100 % clean.

Reference surfaces with a known contamination amount are used to determine limit values of reliable cleanliness.

## SITA **CLEAN LINE (TD)** – Reliable and Robust

- Measures contamination films on part surfaces continually and contact-free
- Avoids problems during coating, bonding, welding, printing or hardening processes
- Displays the cleaning quality directly

#### Application

Line Scan



**Surface Scan** 



**Free Form Scan** 

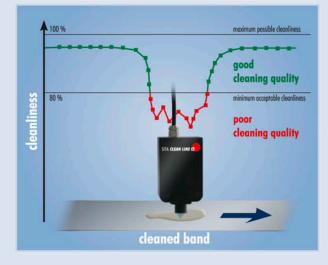


Continual monitoring of band surface cleanliness with one or more sensors

Detecting the cleanliness profile of part surfaces with an X-Y positioning system

Measuring the cleanliness of part surfaces with a 3D positioning system

### Practical Example: Inspection of Band Steel



High cleanliness standards for the coating of band steel assure a high coating quality in the process. SITA clean line CI measures fluorescence continually and detects even the smallest amounts of contamination.

The cleaning process can be immediately interrupted when cleanliness values fall below defined limit values.

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The flexible, customer-specific integration of single or multiple sensor solutions of the SITA clean line CI is used in production processes for the inspection of the smallest parts of medical technology as well as band surfaces in the steel industry.

SITA Advanced Cleaning Control

#### **Technical Data**

#### Sensor SITA clean line Cl

Housing	Anodized oluminum IP51
Interface	RS-485 per Bus or point-to-point topology
Meosured Volue	Cleonliness or relative fluarescence related to SITA Fluarescence Standard
Meosurement Speed	Moximum of 100 individual meosurements per second (100 Hz)
Surfoce Speed	Moximum 10 m / s
Dimensions (W x H x D)	50 mm $\times$ 95 mm $\times$ 30 mm
Weight	200 g

#### **Operational Conditions**

Relative Humidity Surrounding Temperature Moximum 70 % 10 ... 50 °C

#### **Measured Value Cleanliness**

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Measuring Range	0 100 % Cleanliness (100 % correspond to o calibrotion standard with ideal cleonliness volues)
Resolution	0.1 %
Measured Value Fluorescence	
Diometer Meosuring Point	lmm
Meosurement Distonce	4 mm
Wavelength Excitation	365 nm
Wavelength Meosurement	460 nm
Measuring Range	0 1,000 RFU (Relative Fluorescence Unit), SITA Fluorescence Standard N1 = 100 RFU
Error of Meosurement	Moximum 0.5 % of meosuring ronge

Resolution

#### Moximum 0.5 % of meosuring ronge 0.1 RFU

#### **Process-specific System Solution**



The measuring system SITA clean line CI can be adjusted to each customer's unique inspection tasks.

Used with on industrial PC or on SPS with touch panel, the central control unit of the SITA cleon line CC ollows process-specific system solutions to be realized. The customized software controls the cleonliness inspection, soves and visualizes the measured data and communicates with superordinate process controls.

Upon the basis of a combined analysis of process and plant, SITA application engineers develop the SITA clean line system solutions to be adapted to each customer's specific set of criterio.

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